## Silicon P Channel MOS FET Series Power Switching / Over Temperature Shut–down Capability

# HITACHI

ADE-208-583 A (Z) 2nd Edition October 1997

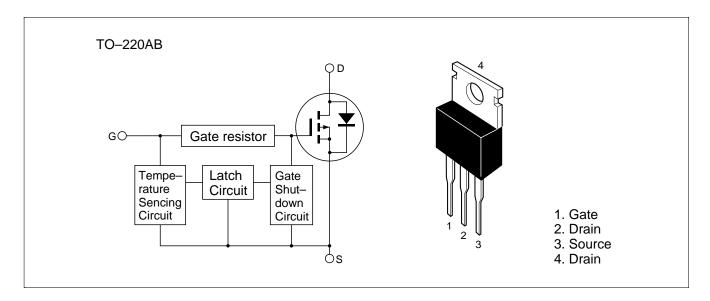
#### Features

This FET has the over temperature shut-down capability sensing to the junction temperature.

This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

- Logic level operation (-4 to -6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut–down operation (Need 0 voltage recovery)

#### Outline





## **Absolute Maximum Ratings** ( $Ta = 25^{\circ}C$ )

Item	Symbol	Ratings	Unit	
Drain to source voltage	V <sub>DSS</sub>	-60	V	
Gate to source voltage	V <sub>GSS+</sub>	-16	V	
Gate to source voltage	V <sub>GSS-</sub>	3	V	
Drain current	I <sub>D</sub>	-15	A	
Drain peak current	Note1 D(pulse)	-30	A	
Body-drain diode reverse drain current	I <sub>DR</sub>	-15	A	
Channel dissipation	Pch Note2	50	W	
Channel temperature	Tch	150	°C	
Storage temperature	Tstg	-55 to +150	°C	

Note: 1.  $PW \le 10\mu s$ , duty cycle  $\le 1 \%$ 

2. Value at Tc =  $25^{\circ}$ C

## **Typical Operation Characteristics**

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Input voltage	V <sub>IH</sub>	-3.5	—	—	V	
	V <sub>IL</sub>	_	—	-1.2	V	
Input current	I <sub>IH1</sub>		_	-100	μA	$Vi = -8V, V_{DS} = 0$
(Gate non shut down)	I <sub>IH2</sub>		_	-50	μA	$Vi = -3.5V, V_{DS} = 0$
	Ι <sub>IL</sub>			-1	μA	$Vi = -1.2V, V_{DS} = 0$
Input current	I IH(sd)1		-0.8		mA	$Vi = -8V, V_{DS} = 0$
(Gate shut down)	I <sub>IH(sd)2</sub>		-0.35	_	mA	$Vi = -3.5V, V_{DS} = 0$
Shut down temperature	T <sub>sd</sub>		175		°C	Channel temperature
Gate operation voltage	V <sub>OP</sub>	-3.5		-13	V	

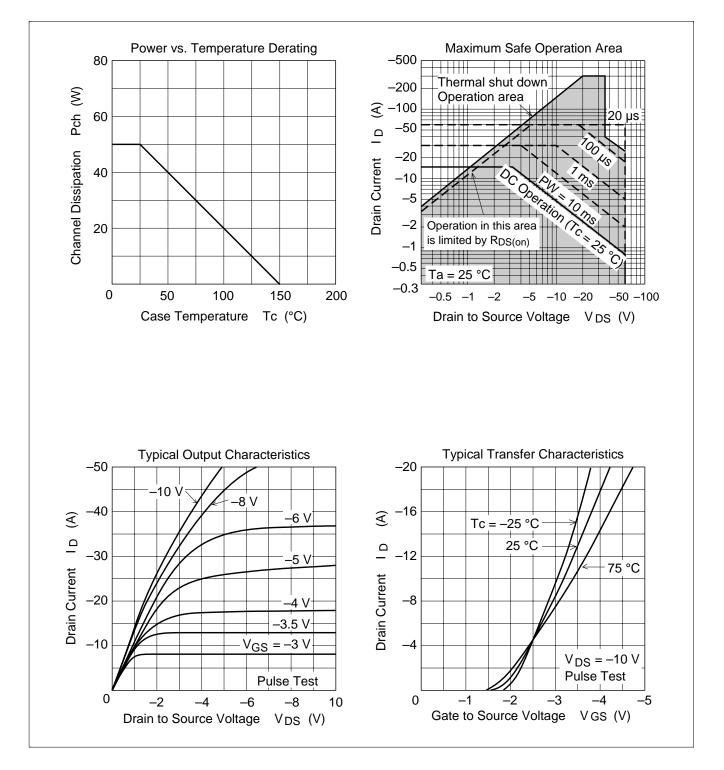
#### **Electrical Characteristics** (Ta = 25°C)

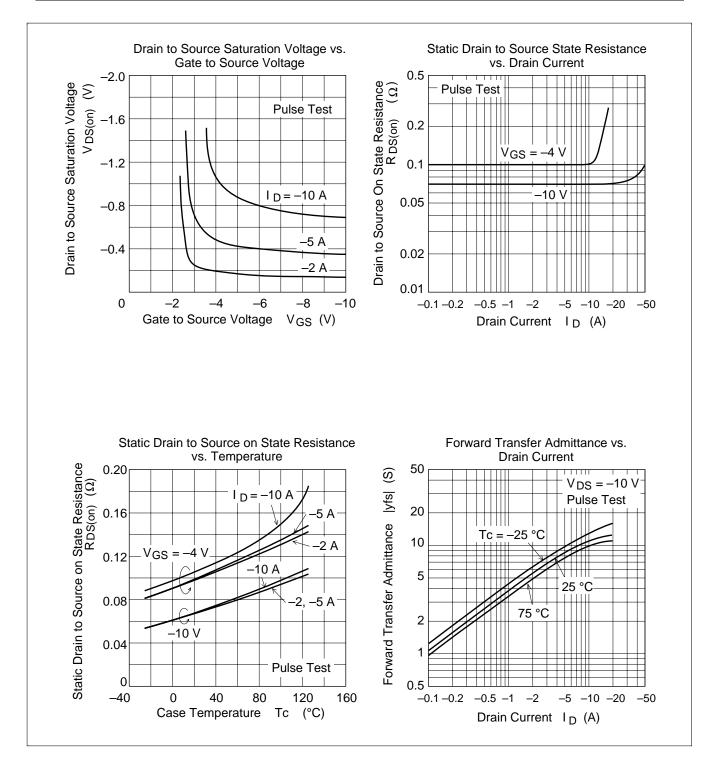
Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain current	I <sub>D1</sub>	-7	_		А	$V_{GS} = -3.5V, V_{DS} = -2V$
Drain current	I <sub>D2</sub>	_		-10	mA	$V_{GS} = -1.2V, V_{DS} = -2V$
Drain to source breakdown voltage	V <sub>(BR)DSS</sub>	-60		_	V	$I_{\rm D} = -10$ mA, $V_{\rm GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS+}$	-16	·		V	$I_{G} = -100 \mu A, V_{DS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS-}$	3	_	_	V	$I_{\rm G} = 100 \mu A, V_{\rm DS} = 0$
Gate to source leak current	I <sub>GSS+1</sub>	_		-100	μA	$V_{\rm GS} = -8V, V_{\rm DS} = 0$
	I <sub>GSS+2</sub>	_		-50	μA	$V_{GS} = -3.5V, V_{DS} = 0$
	I <sub>GSS+3</sub>			-1	μA	$V_{GS} = -1.2V, V_{DS} = 0$
	I <sub>GSS-</sub>	_		100	μΑ	$V_{GS} = 2.4V, V_{DS} = 0$
Input current (shut down)	I <sub>GS(op)1</sub>	·	-0.8		mA	$V_{GS} = -8V, V_{DS} = 0$
	I <sub>GS(op)1</sub>		-0.35		mA	$V_{GS} = -3.5V, V_{DS} = 0$
Zero gate voltege drain current	t I <sub>DSS</sub>			-250	μA	$V_{\rm DS} = -50$ V, $V_{\rm GS} = 0$
Gate to source cutoff voltage	V <sub>GS(off)</sub>	-1.1		-2.25	V	$I_{\rm D} = -1$ mA, $V_{\rm DS} = -10$ V
Static drain to source on state resistance	$R_{\text{DS(on)}}$	—	100	130	mΩ	$I_{\rm D} = -7.5$ A, $V_{\rm GS} = -4$ V <sup>Note3</sup>
Static drain to source on state resistance	R <sub>DS(on)</sub>		70	90	mΩ	$I_{D} = -7.5A$ $V_{GS} = -10V^{Note3}$
Forward transfer admittance	y <sub>fs</sub>	5	10		S	$I_{\rm D} = -7.5$ A, $V_{\rm DS} = -10$ V
Output capacitance	Coss	_	610	_	pF	$V_{\rm DS} = -10V$ , $V_{\rm GS} = 0$
						f = 1 MHz
Turn-on delay time	t <sub>d(on)</sub>		7.5		μs	I <sub>D</sub> = -7.5A, V <sub>GS</sub> = -5V
Rise time	t <sub>r</sub>		36	_	μs	$R_{L} = 4\Omega$
Turn-off delay time	t <sub>d(off)</sub>	_	32		μs	
Fall time	t <sub>r</sub>	_	29		μs	
Body-drain diode forward	V <sub>DF</sub>	_	-1.0		V	$I_{\rm F} = -15 {\rm A},  V_{\rm GS} = 0$
voltage						
Body-drain diode reverse	t <sub>rr</sub>	_	200		ns	$I_{\rm F} = -15 {\rm A},  {\rm V}_{\rm GS} = 0$
recovery time						diF/ dt =50A/µs
Over load shut down	t <sub>os1</sub>		3.7	_	ms	$V_{GS} = -5V, V_{DD} = -12V$
operation time Note4	t <sub>os2</sub>		1		ms	$V_{\rm GS} = -5V, V_{\rm DD} = -24V$
Nata: 0 Dulas test						

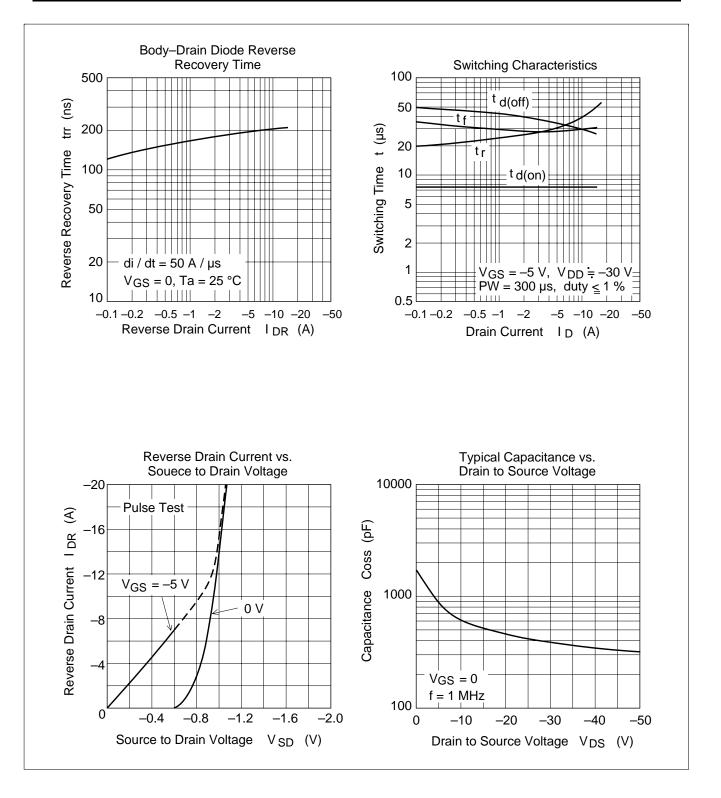
Note: 3. Pulse test

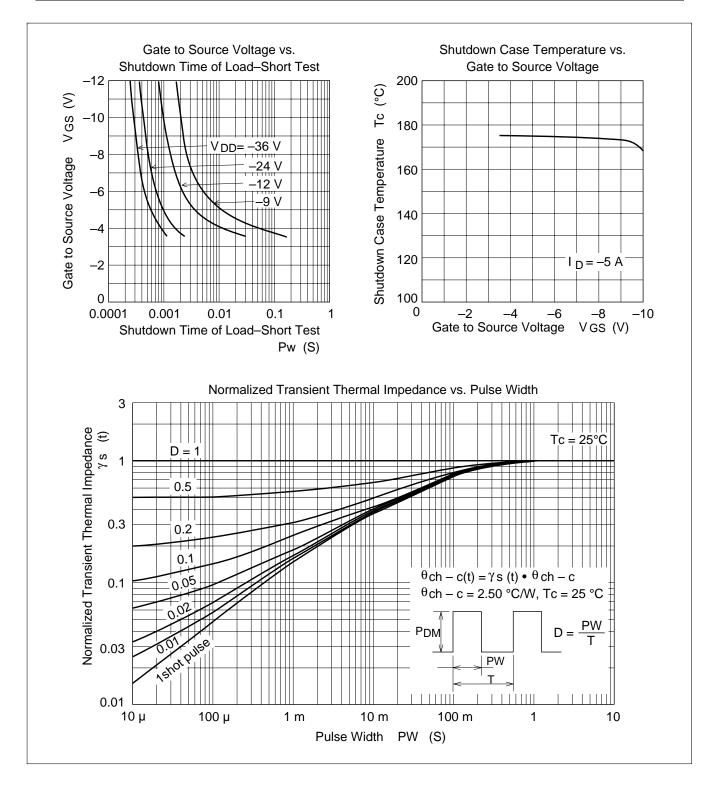
4. Including the junction temperature rise of the over loaded condition.

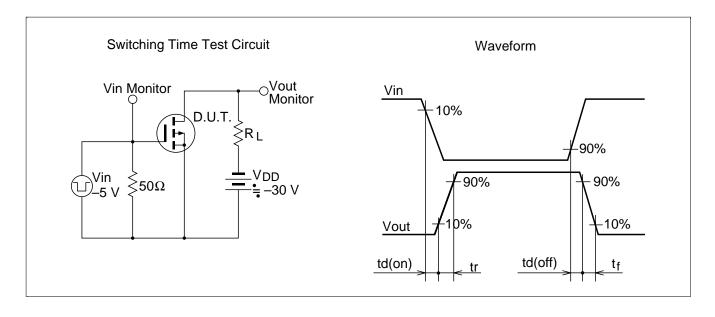
#### **Main Characteristics**











Unit: mm

## **Package Dimensions**

11.5 max 3.0max f 3.6<sup>+0.1</sup> 4.8 max 9.8 max 1.27 7.6 min <u>1.5 max</u> .6.3 min + 15.3 max 18.5 ±0.5 1.5 max 12.7 min 0.5 7.8±0.5 0.76 ±0.1 TO-220AB Hitachi Code 2.5 ±0.5 <u>2.7 max</u> EIAJ 5.1 ±0.5 SC-46 JEDEC \_\_\_\_

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